

HR3: First measurements

OMEGA, 22/11/2013

OMEGA microelectronics group

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Organization for Micro-Electronics desiGn and Applications

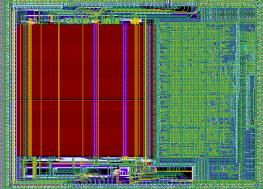
HARDROC3

- **3**rd generation chip for ILD
 - Independent channels (zero suppress)

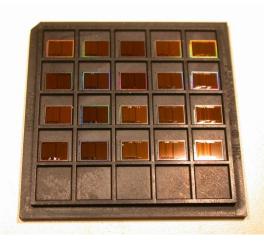
I2C link (@IPNL) for Slow Control parameters and triple voting

□ HARDROC3: 1st of the 3rd generation chip to be submitted

- analog part: extension of the dynamic
- PLL: integrated to generate clocks internally
- Submitted in Feb 2013 (SiGe 0.35 μ m), funded by AIDA, received end of June 2013
- Die size ~30 mm² (6.3 x 4.7 mm²)
- Packaged in a QFP208,
- HR3 will equip 2-3m RPC chambers

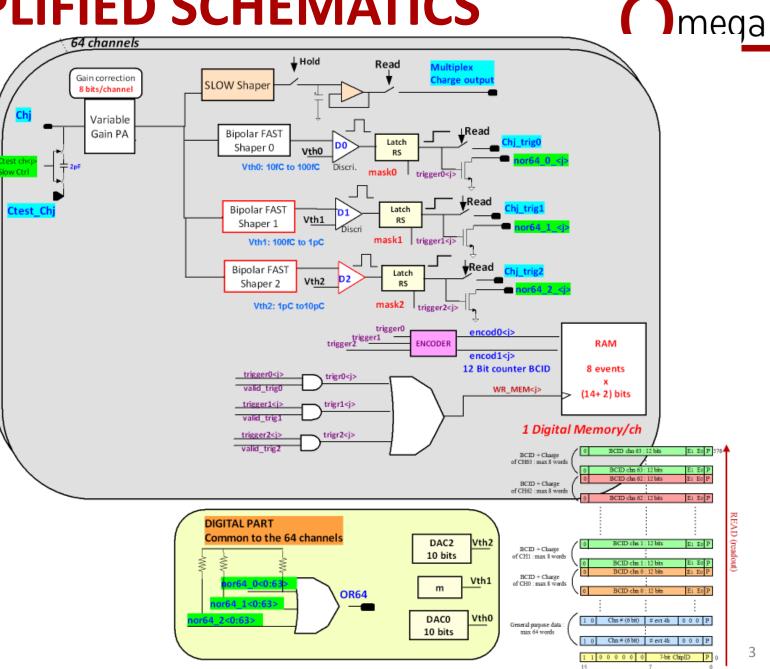








SIMPLIFIED SCHEMATICS

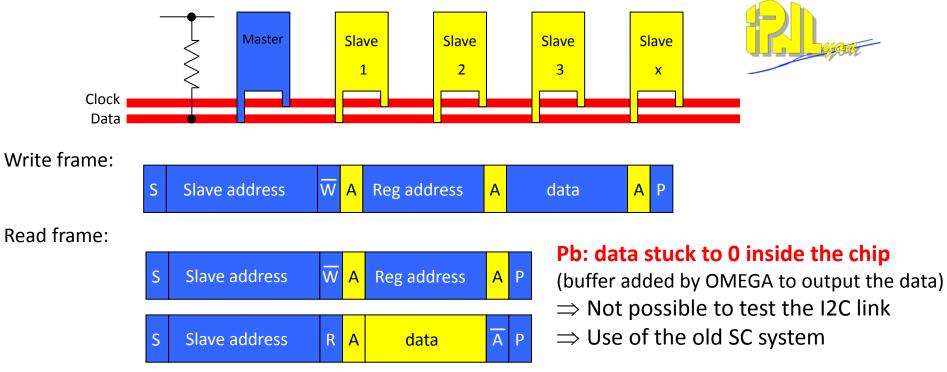


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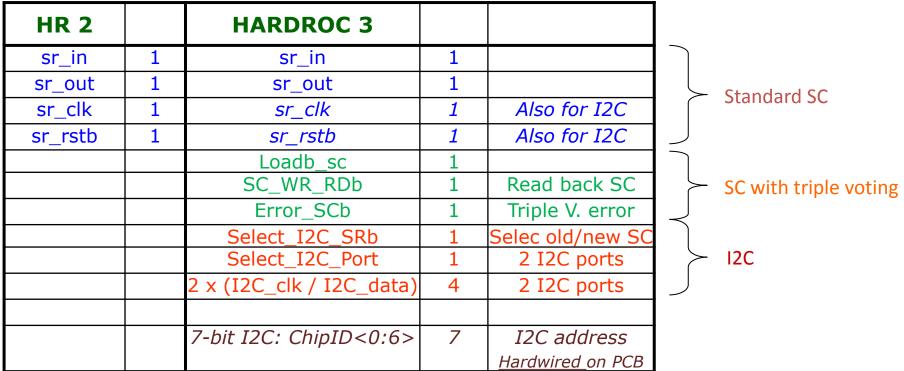
3rd generation: Slow Control parameters

- Slow control parameters:
 - Backward compatibility with 2Gen ROC chips slow control
 - Use of classical shift register slow control
 - Embedded I2C
 - 7-bit address + 1 general call address (127 chips can be addressed)
 - Access port doubled
 - Bidirectional data line with open collector (Driver will be the same as Dout)
 - Read back capability of SC bits (non destructive)

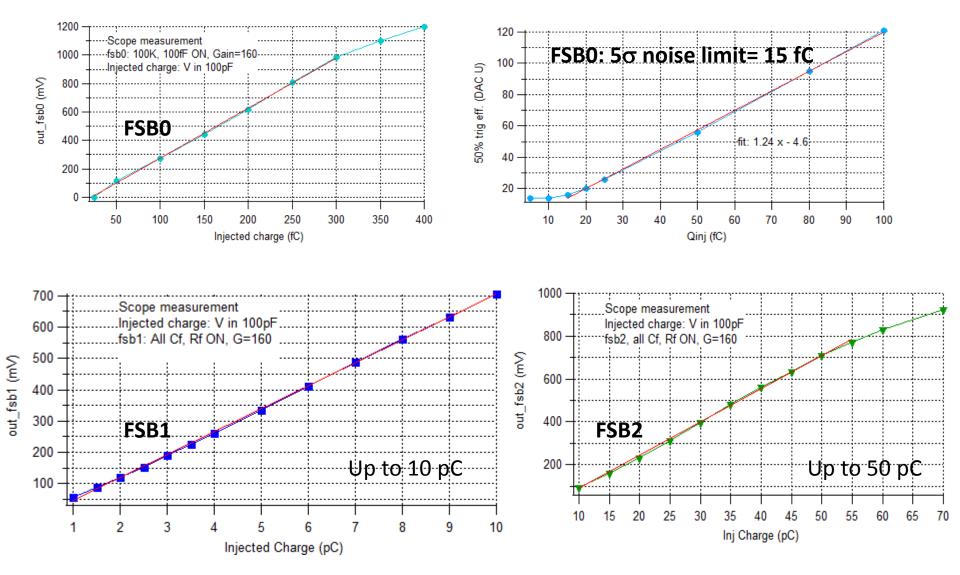


3rd generation SC

- Extra pin needed for I2C / SC:
- Possibility to choose between old SC registers/ New I2C link (Select_I2C_SRb) available on one pin)

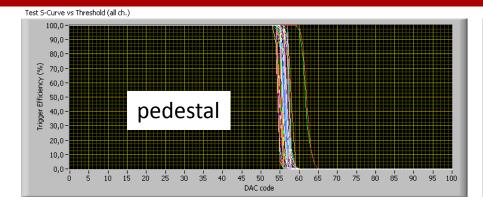


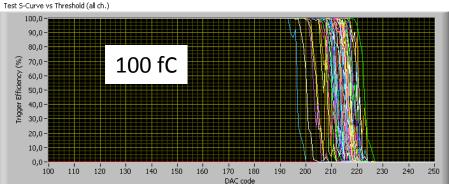
ANALOG PART: FSB LINEARITY Omega

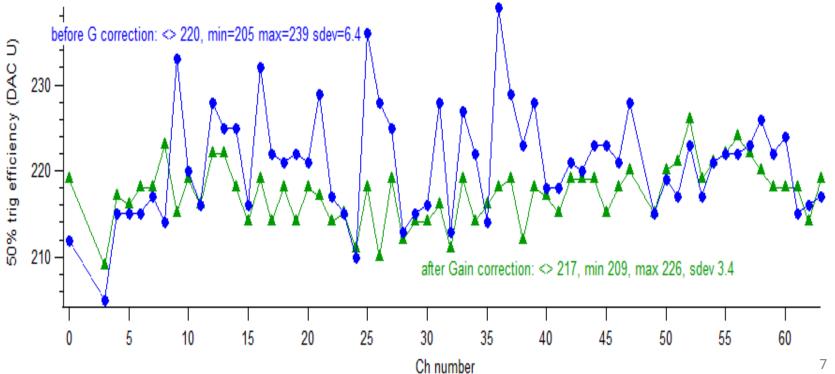


SCURVE MEASUREMENTS

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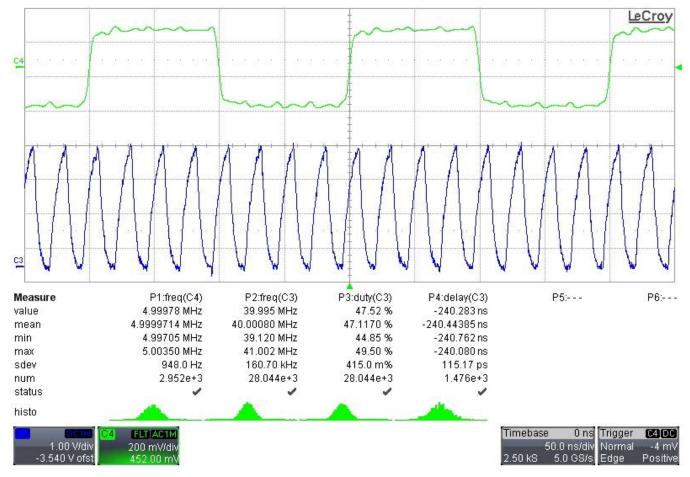


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HR3: PLL tests

Input LVDS clock @ 5 MHz:

- \Rightarrow Mult factor = N+1 = 8
- \Rightarrow Output freq of PLL = 40 MHz
- \Rightarrow Full chain tested with charge injected on chn 31 and readout on serial link



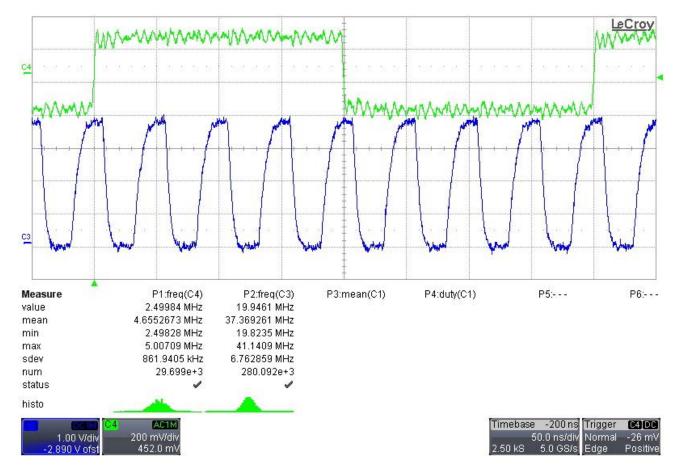
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HR3: PLL tests



Input LVDS clock @ 2,5 MHz:

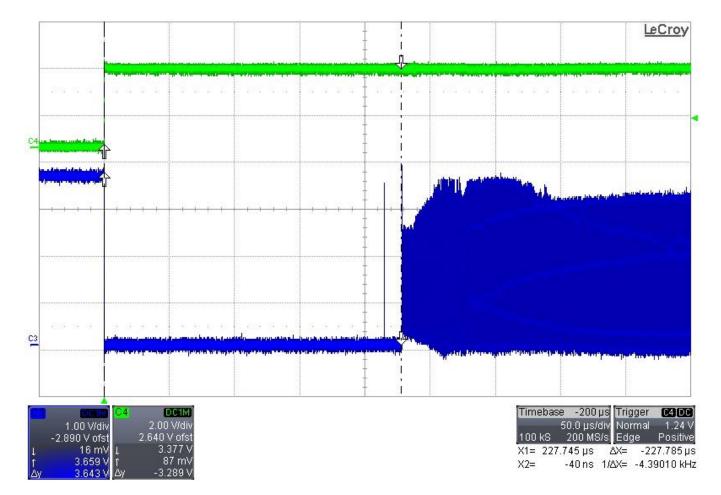
- \Rightarrow Mult factor = N+1 = 8
- \Rightarrow Output freq of PLL = 20 MHz
- \Rightarrow Full chain tested with charge injected on chn 31 and readout on serial link



HR3: PLL lock time

Lock time (start time):

- \Rightarrow Green = PowerOnD / Blue = Out_PLL
- \Rightarrow Time needed to have a stable clock = 230 + 30 = 260 μs

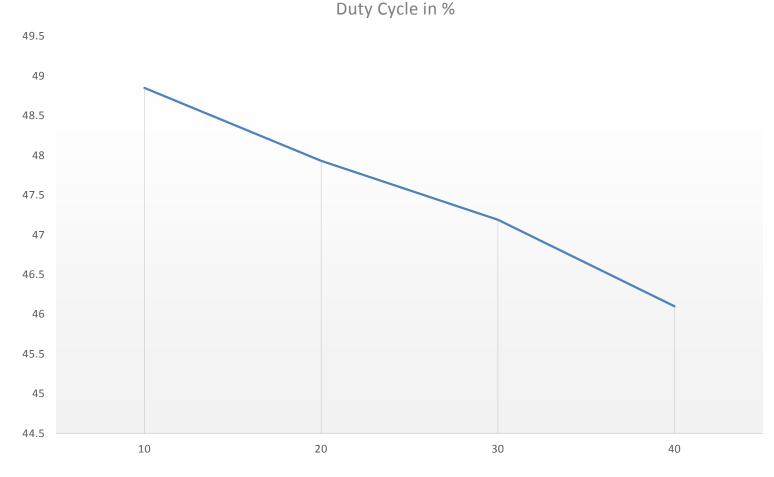


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HR3: PLL Duty cycle

Input LVDS clock @ 5 MHz:

- \Rightarrow Mult factor = 2 / 4 / 8 / 16
- \Rightarrow X = freq of Out_PLL
- \Rightarrow Y = duty cycle in %



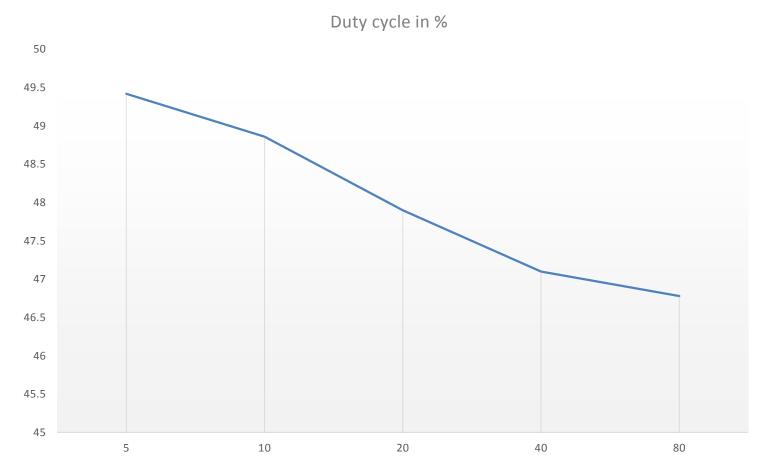
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HR3: PLL duty cycle

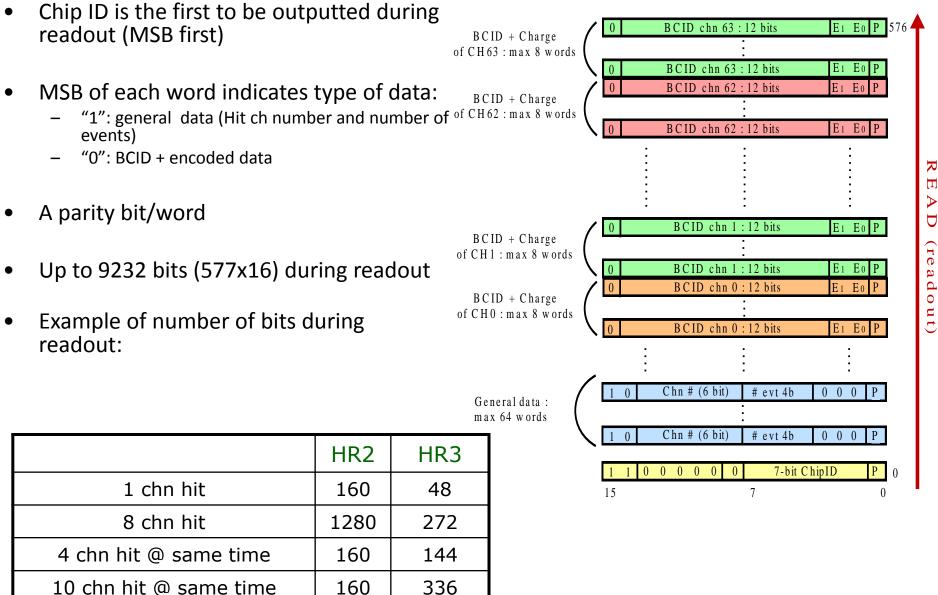
Input LVDS clock @ 2,5 MHz:

- \Rightarrow Mult factor = 2 / 4 / 8 / 16 / 32
- \Rightarrow X = freq of Out_PLL
- \Rightarrow Y = duty cycle in %



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HARDROC 3 : Memory mapping



HARDROC 3 : digital part



• Zero suppress (only hit channels are readout): test OK

Setup	Slow Co	Control 1 Slow Control 2 SCA Read, Temp. Fl				FPC	GA Configuration Info HAI				ARDRO	OC3 I2C test Info p				pcb I/O Info pcb Test			est	Mixed Test: S-Curve (Threshold)							
Mixed Test: 5-Curve (Threshold) all Ch. Analogue Test: DAC							Analogue Test: DC					External ADC External ADC c						calib	alib Digital ASIC Debug / DAQ								
Step by Step DAQ Reset ASIC Digital Start Acquisition FPGA External Trigger Start ReadOut1 Start ReadOut2						E	hipSat nd Rea			Frame received OK ? OK Nb of bits read in ASIC RAM 304 Chip ID 2 100111					Automatic DAQ Automatic DAQ Automatic DAQ Automatic DAQ ChipSatb must be enabled SlowClock -> CLK_GENE_EXT Nb of Acquisitions 10 TimeDut for 1 Acq/Conv/R0 10ms (Slow Clock @ 5MH2) \[Current Acquisition							Data Analysis Clean DAQ data folder Analyze saved data now ! Files data loading					
ASIC Memory (Raw Data) Decoded Data Signal injected only in ch 20 and 43														1													
													Sig	nal i	inje	cte	d o	nly	in c	h 2	.0 a	nd	43				
HR3 Decoded Data														_	_												
Ch	nannel #	20	20	20	20	20	20	20	20	43	43	43	43	43	43	43	43	0	0	0	0	0	0	0	0	0	
ВС	ID	3753	3253	2753	2253	1753	1253	753	253	3753	3253	2753	2253	1753	1253	753	253	0	0	0	0	0	0	0	0	0	
E1	l / EO	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	

- Roll mode SC : test OK
 - If RollMode = "0" → Backward compatibility with 2Gen ROC chips behavior
 - Only the N first events are stored
 - If RollMode = "1" → 3Gen ROC chips behaviour
 - Use the circular memory mode
 - Only the N last events are stored
- "Noisy Evt" SC: 64 triggers => Noisy event => no data stored : test OK
- "ARCID" SC (Always Read Chip ID): test OK
 - If ARCID = 0 \rightarrow Backward compatibility: No event \rightarrow No readout
 - − If ARCID= 1 → New behavior: No event → Read CHIP ID

Summary and next steps

- Good analog performance:
 - dynamic range extended up to 50 pC
 - PLL => clocks generated internally
- Preliminary good digital performance
 - Zero suppress, roll mode, ARCID mode, Noisy evt mode tested successfully on testboard
 - External trigger available to be able to check the status of each channel
- I2C link
 - FIB on 2 chips to test the link
- 2-3m long RPC chambers to be built and equipped with HR3 in 2014

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